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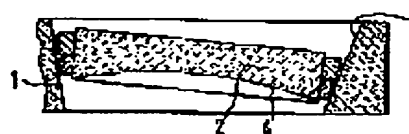
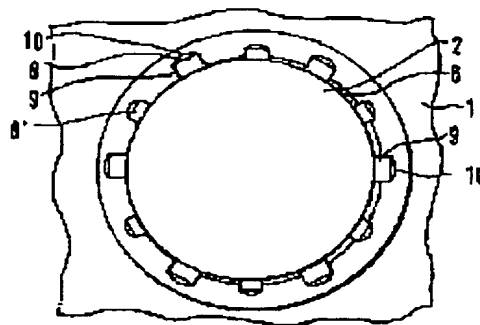
(54) DIODE ARRAY SPECTROPHOTOMETER

(57)Abstract:

PROBLEM TO BE SOLVED: To stably secure a diffraction grating thermally and mechanically with respect to an inlet slit and a diode array by providing the subject photometer with a casing for determining the relative position between them.

SOLUTION: A casing 1 for determining the relative position between an inlet slit and a diode array has a frustum conical opening 7 enlarging outward and made of silicate ceramic. A diffraction grating holder 2 (made of silicate ceramic) comprises a cylindrical body having cylindrical outer surface 6 and a diffraction grating 4 similar to a concave mirror is secured to the body. A plurality of filling elements 8, 8' are arranged between the cylindrical outer surface 6 of diffraction grating holder

2 and the wall of frustum conical opening 7. The filling element 8, 8' has cylindrical base part 9 and spherical upper part 10. The diffraction grating holder 2 is inserted into the opening 7 and adjusted. Flat base part of the filling element 8, 8' abuts against the outer surface 6 and the spherical upper part 10 abuts against the opening 7.



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